

Application/Control No.	Applicant(s)/Patent under Reexamination
09/848,953	HICKERSON ET AL.
Examiner	Art Unit

Sheela C. Chawan

2624

SEARCHED					
Class	Subclass	Date	Examiner		
382	173	10/23/2006	scc		
11	187	10/23/2006	"		
n	292	10/23/2006			
704	232	10/23/2006	n		
11	227	10/23/2006	н		
"	228	10/23/2006	n		
"	256	10/23/2006	"		
ABOVE	SEARCH	10/23/2006	н		
UP-DAT.					
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST, US-PGPUB,USPAT, EPO,JPO,DERWENT,IBM- TDB, SEE ATTACHED SEARCH HISTORY.	10/23/2006	scc		
382/187, 155,173,229,292.CCLS. 345/467.CCLS. 704/232,227,228,256.CCLS. US-PATENT ONLY, SEE TEXT SEARCH.	10/23/2006			
INTERFERENCE SEARCH, SEE SEARCH HISTORY PRINT OUT.	10/23/2006	"		
INVENTOR NAME SEARCH.	10/23/2006	n		
IEEE OR INSPEC DATA BASE SEARCH .	10/23/2006	n		
ABOVE SEARCH UP DATE.	10/23/2006	n		